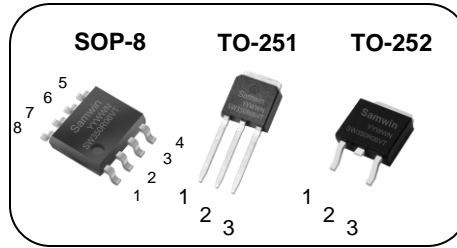


### N-channel Enhanced mode SOP-8/TO-251/TO-252 MOSFET

#### Features

- High ruggedness
- SOP-8 Low  $R_{DS(ON)}$   
(Typ 38mΩ)@ $V_{GS}=4.5V$   
(Typ 33mΩ)@ $V_{GS}=10V$
- TO-251&TO-252 Low  $R_{DS(ON)}$   
(Typ 37mΩ)@ $V_{GS}=4.5V$   
(Typ 32mΩ)@ $V_{GS}=10V$
- Low Gate Charge (Typ 21nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: DC-DC Converter, Motor Control, Synchronous Rectification, Inverter



SOP-8:4.Gate 5,6,7,8.Drain 1,2,3.Source  
TO-251:1.Gate 2.Drain 3.Source

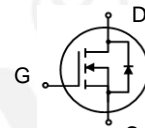
$BV_{DSS}$  : 60V

SOP8  $I_D$  : 5A

$R_{DS(ON)}$  : 38mΩ@ $V_{GS}=4.5V$   
33mΩ@ $V_{GS}=10V$

TO-251 & TO-252  $I_D$  : 24A

$R_{DS(ON)}$  : 37mΩ@ $V_{GS}=4.5V$   
32mΩ@ $V_{GS}=10V$



#### General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

#### Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW K 350R06VT	SW350R06VT	SOP-8	REEL
2	SW I 350R06VT	SW350R06VT	TO-251	TUBE
3	SW D 350R06VT	SW350R06VT	TO-252	REEL

#### Absolute maximum ratings

Symbol	Parameter	Value			Unit
		SOP-8	TO-251	TO-252	
$V_{DSS}$	Drain to source voltage	60			V
$I_D$	Continuous drain current (@ $T_C=25^\circ C$ )	5*	24*		A
	Continuous drain current (@ $T_C=100^\circ C$ )	3*	17*		A
$I_{DM}$	Drain current pulsed (note 1)	20	96		A
$V_{GS}$	Gate to source voltage	±20			V
dv/dt	Peak diode recovery dv/dt (note 2)	5			V/ns
$P_D$	Total power dissipation (@ $T_C=25^\circ C$ )		104	65.8	W
	Total power dissipation (@ $T_a=25^\circ C$ )	2.6			
	Derating factor above 25°C	0.02	0.8	0.5	W/°C
$T_{STG}, T_J$	Operating junction temperature & storage temperature	-55 ~ + 150			°C
$T_L$	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds.	300			°C

\*. Drain current is limited by junction temperature.

#### Thermal characteristics

Symbol	Parameter	Value			Unit
		SOP-8	TO-251	TO-252	
$R_{thjc}$	Thermal resistance, Junction to case		1.2	1.9	°C/W
$R_{thja}$	Thermal resistance, Junction to ambient	48	85.2		°C/W

Note:  $R_{thja}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{thjc}$  is guaranteed by design while  $R_{thca}$  is determined by the user's board design.



SOP-8  $R_{thja}$  : 48°C/W on a 1 in<sup>2</sup> pad of 2oz copper.

## Electrical characteristic ( $T_C = 25^\circ\text{C}$ unless otherwise specified )

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
<b>Off characteristics</b>						
$BV_{DSS}$	Drain to source breakdown voltage	$V_{GS}=0V, I_D=250\mu A$	60			V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown voltage temperature coefficient	$I_D=250\mu A$ , referenced to $25^\circ\text{C}$		0.06		$V/^\circ\text{C}$
$I_{DSS}$	Drain to source leakage current	$V_{DS}=60V, V_{GS}=0V$			1	$\mu A$
		$V_{DS}=48V, T_C=125^\circ\text{C}$			50	$\mu A$
$I_{GSS}$	Gate to source leakage current, forward	$V_{GS}=20V, V_{DS}=0V$			100	nA
	Gate to source leakage current, reverse	$V_{GS}=-20V, V_{DS}=0V$			-100	nA
<b>On characteristics</b>						
$V_{GS(TH)}$	Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2		2.5	V
$R_{DS(ON)}$	Drain to source on state resistance (SOP-8)	$V_{GS}=4.5V, I_D=5A$		38	47	$m\Omega$
		$V_{GS}=10V, I_D=5A$		33	41	
	Drain to source on state resistance (TO-251&TO-252)	$V_{GS}=4.5V, I_D=12A$		37	46	$m\Omega$
		$V_{GS}=10V, I_D=12A$		32	40	
$G_{fs}$	Forward transconductance(SOP-8)	$V_{DS}=5V, I_D=2.5A$		14		S
	Forward transconductance (TO-251&TO-252)	$V_{DS}=5V, I_D=12A$		35		S
<b>Dynamic characteristics</b>						
$C_{ISS}$	Input capacitance			962		pF
$C_{OSS}$	Output capacitance	$V_{GS}=0V, V_{DS}=30V, f=1\text{MHz}$		66		
$C_{RSS}$	Reverse transfer capacitance			47		
$t_{d(on)}$	Turn on delay time			4		ns
$t_r$	Rising time	$V_{DS}=30V, I_D=5A, R_G=25\Omega, V_{GS}=10V$		29		
$t_{d(off)}$	Turn off delay time	$(\text{note } 3,4)$		82		
$t_f$	Fall time			38		
$Q_g$	Total gate charge	$V_{DS}=48V, V_{GS}=10V, I_D=5A, I_g=3\text{mA}$		21		nC
$Q_{gs}$	Gate-source charge	$(\text{note } 3,4)$		3		
$Q_{gd}$	Gate-drain charge			5		
$R_g$	Gate resistance	$V_{DS}=0V, \text{Scan F mode}$		6.0		

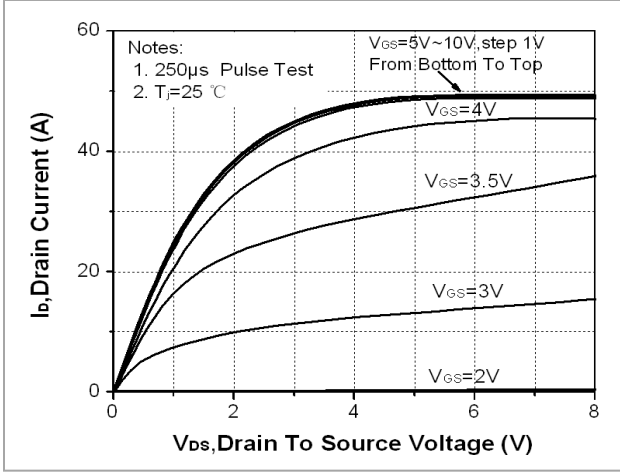
## Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.			Unit
					SOP-8	TO-251	TO-252	
$I_S$	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			5	24		A
$I_{SM}$	Pulsed source current				20	96		A
$V_{SD}$	Diode forward voltage drop	$I_S=5A, V_{GS}=0V(\text{SOP-8})$			1.4			V
		$I_S=24A, V_{GS}=0V(\text{TO-251\&TO-252})$				1.4		
$t_{rr}$	Reverse recovery time	$I_S=5A, V_{GS}=0V,$		16				ns
$Q_{rr}$	Reverse recovery charge	$di_f/dt=100A/\mu s$		3				nC

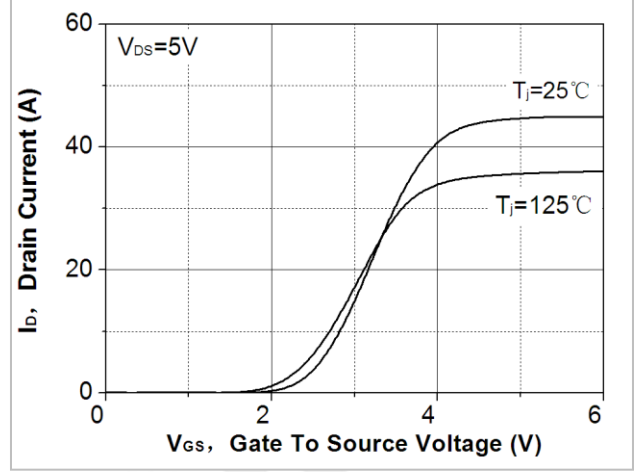
### ※. Notes

1. Repetitive rating : pulse width limited by junction temperature.
2.  $I_{SD} \leq 5A, di/dt = 100A/\mu s, V_{DD} \leq BV_{DSS}, \text{Staring } T_J = 25^\circ\text{C}$
3. Pulse Test : Pulse Width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
4. Essentially independent of operating temperature.

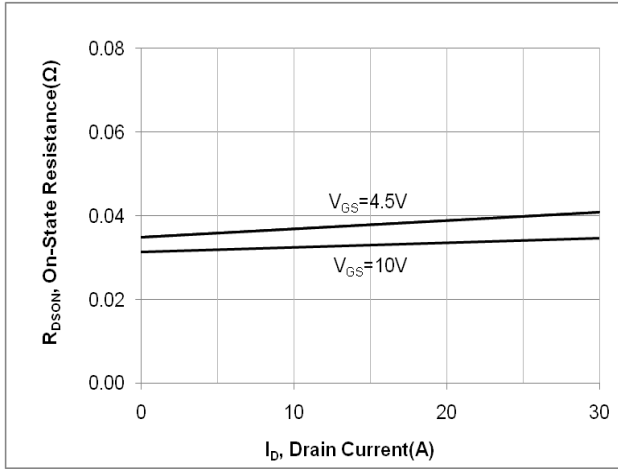
**Fig. 1. On-state characteristics**



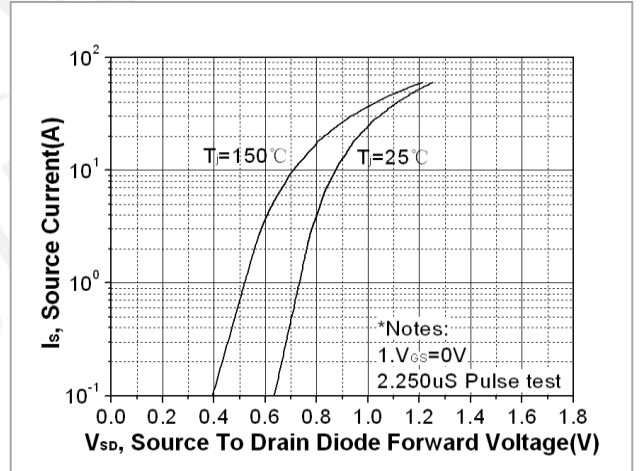
**Fig. 2. Transfer Characteristics**



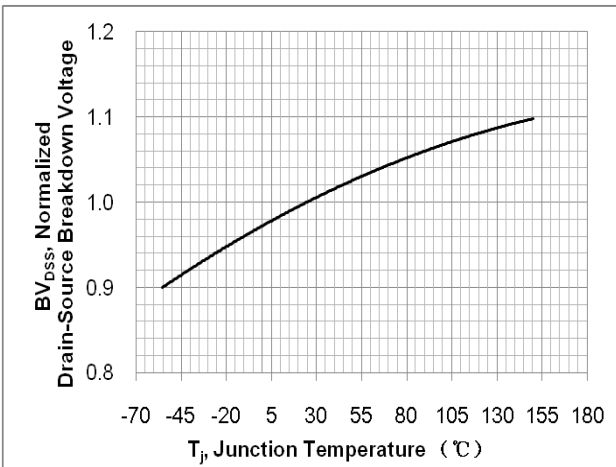
**Fig. 3. On-resistance variation vs. drain current and gate voltage**



**Fig. 4. On-state current vs. diode forward voltage**



**Fig 5. Breakdown voltage variation vs. junction temperature**



**Fig. 6. On-resistance variation vs. junction temperature**

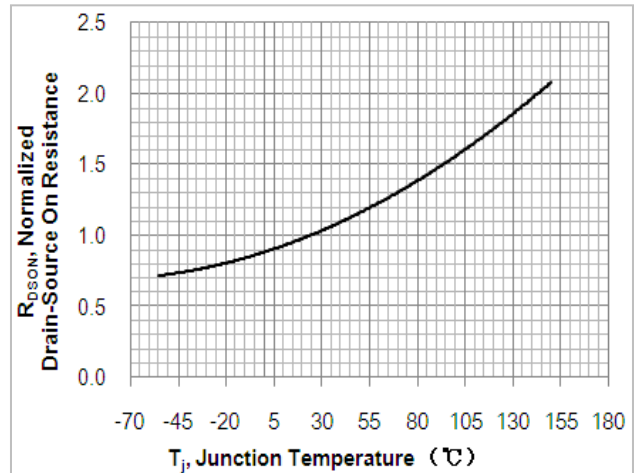


Fig. 7. Gate charge characteristics

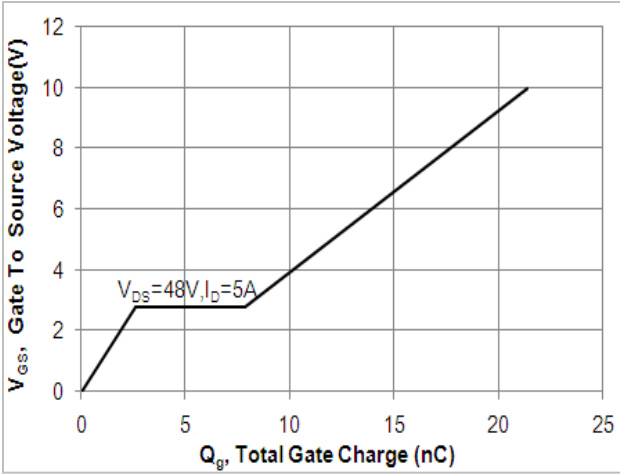


Fig. 8. Capacitance Characteristics

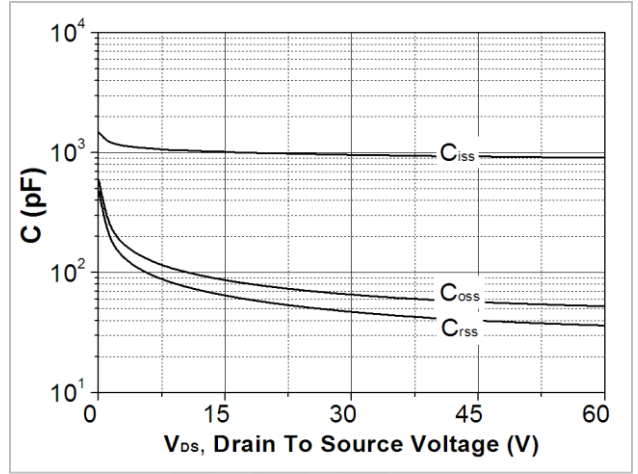


Fig. 9. Maximum safe operating area (SOP-8)

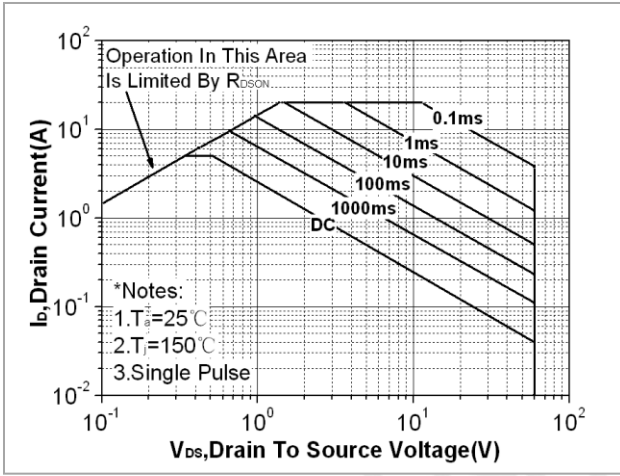


Fig. 10. Maximum safe operating area (TO-251)

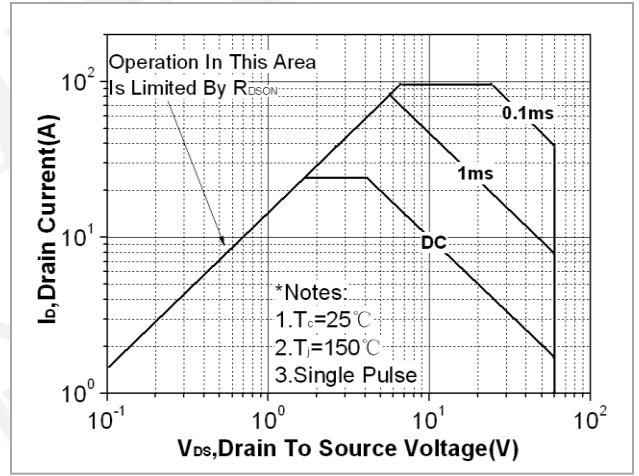


Fig. 11 Maximum safe operating area (TO-252)

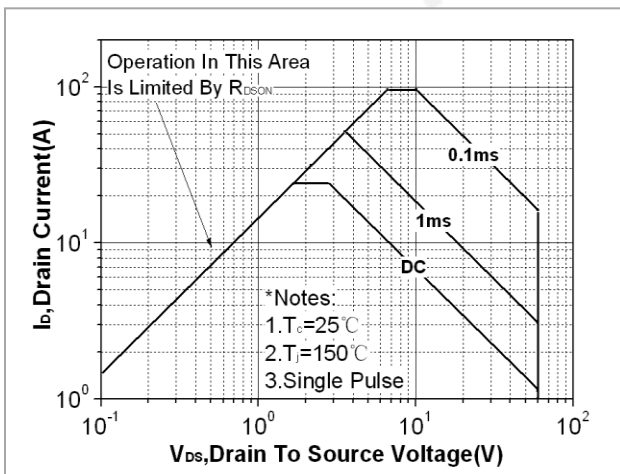


Fig. 12. Transient thermal response curve (SOP-8)

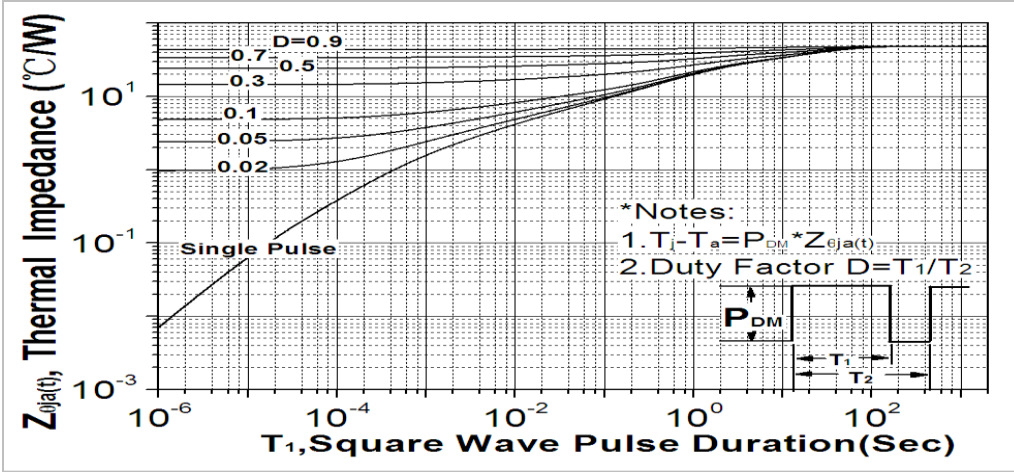


Fig. 13. Transient thermal response curve (TO-251)

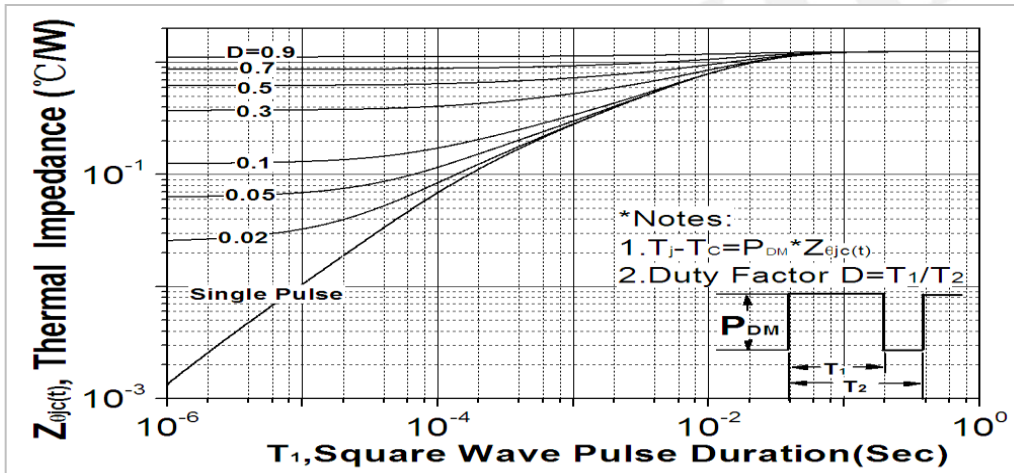
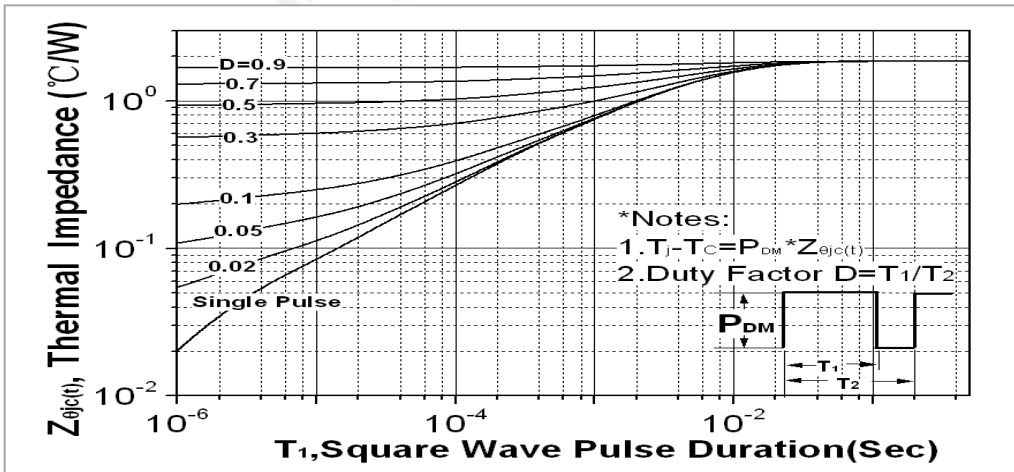
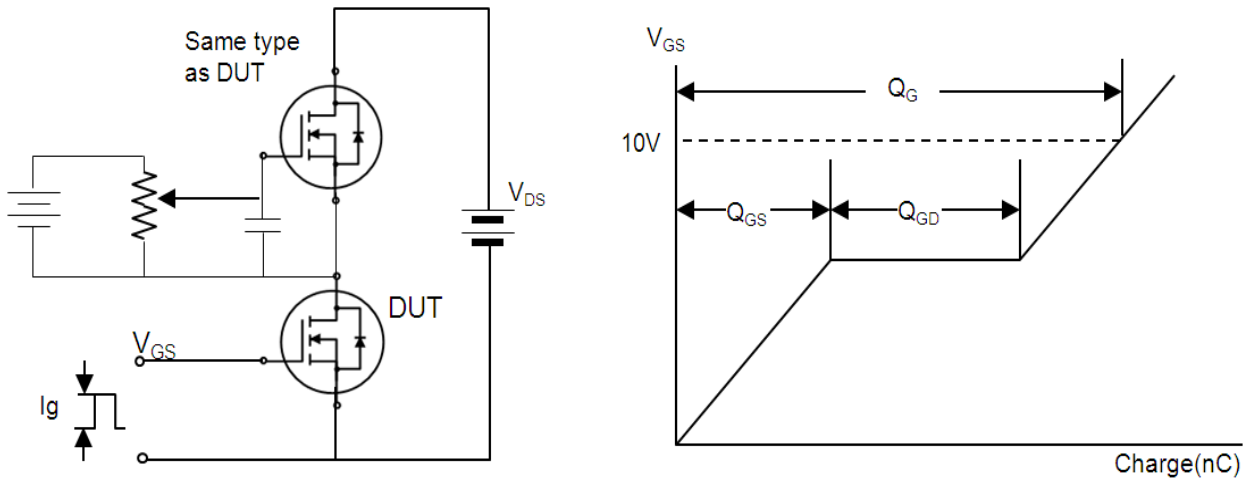


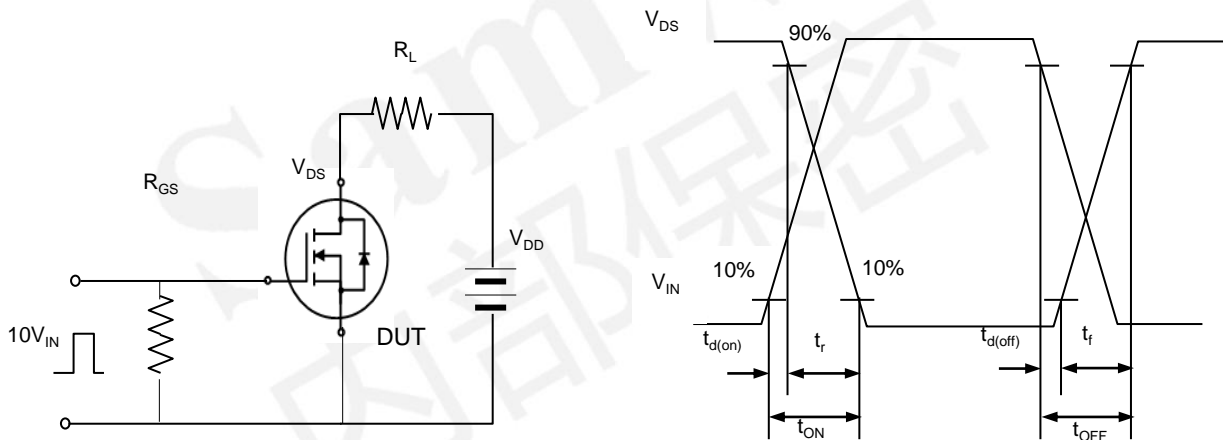
Fig. 14. Transient thermal response curve (TO-252)



**Fig. 15. Gate charge test circuit & waveform**



**Fig. 16. Switching time test circuit & waveform**



**Fig. 17. Unclamped Inductive switching test circuit & waveform**

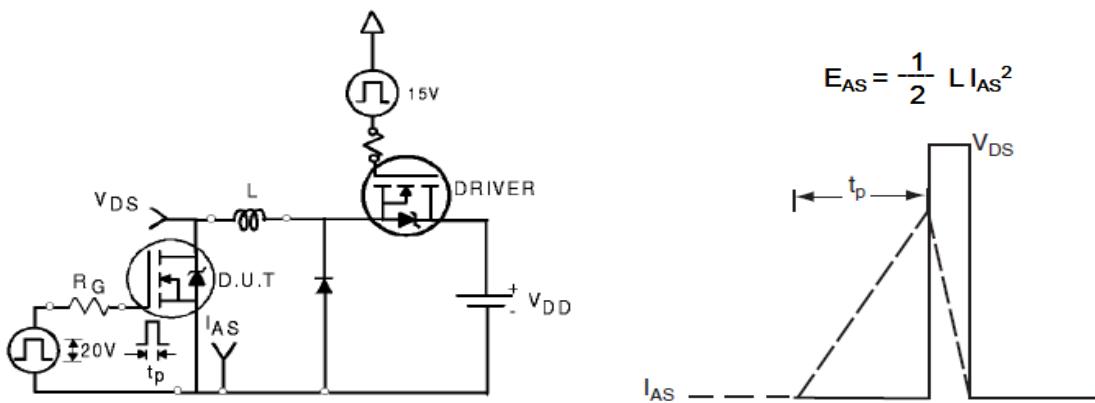
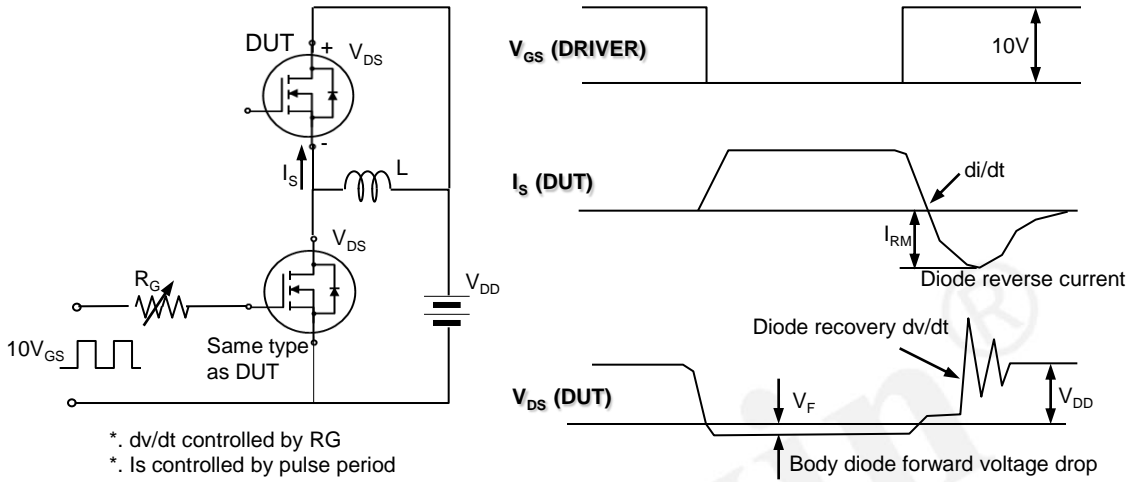



Fig. 18. Peak diode recovery dv/dt test circuit & waveform



### DISCLAIMER

\* All the data & curve in this document was tested in XI' AN SEMIPOWER TESTING & APPLICATION CENTER.

\* This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.

\* Qualification standards can also be found on the Web site (<http://www.semipower.com>). 

\* Suggestions for improvement are appreciated, Please send your suggestions to [samwin@samwinsemi.com](mailto:samwin@samwinsemi.com)